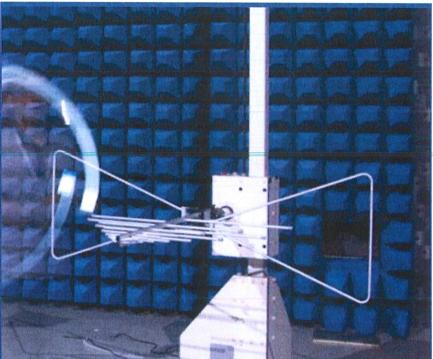


ISSUED BY Shenzhen BALUN Technology Co., Ltd.





401, Building 4, AnTongDa Industrial Park, District 68, XingDong Community, XinAn Street, BaoAn District, Shenzhen, China.





Report No.: EUT Name: Model Name: Brand Name: Test Standard: Test conclusion: Test Date: Date of Issue:

BL-DG2030080-402 Solar Gird-tied Inverter SOFAR 3300TL-G3 (refer section 2.4) **S CAR** Refer Section 3.1 Pass Jul. 02, 2019 ~ Mar. 27, 2020 Apr. 07, 2020

NOTE: This test report of test results only related to testing samples, which can be duplicated completely for the legal use with the approval of the applicant; it shall not be reproduced except in full, without the written approval of Shenzhen BALUN Technology Co., Ltd. Any objections should be raised within thirty days from the date of issue. To validate the report, please contact us.

Room 104, 204, 205, Building 1, No. 6, Industrial South Road, Songshan Lake District, Dongguan, Guangdong, China 523808 TEL: +86-0769-22212330 Email: qc@baluntek.com www.baluntek.com



Revision History

Version <u>Rev. 01</u> Issue Date Apr. 07, 2020 Revisions Content Initial Issue

TABLE OF CONTENTS

1 GENERAL INFORMATION	
1.1 Identification of the Testing Laboratory	4
1.2 Identification of the Responsible Testing Location	4
1.3 Laboratory Condition	4
1.4 Announce	4
2 PRODUCT INFORMATION	5
2.1 Applicant Information	5
2.2 Manufacturer Information	5
2.3 Factory Information	5
2.4 General Description for Equipment under Test (EUT)	5
2.5 Ancillary Equipment	6
2.6 Technical Information	6
3 SUMMARY OF TEST RESULTS	8
3.1 Test Standards	
3.2 Verdict	9
3.3 Test Uncertainty	
4 GENERAL TEST CONFIGURATIONS	11
4.1 Test Environments	11
4.2 Test Equipment List	11
4.3 Test Enclosure list	
4.4 Test Configurations	
4.5 Description of Test Setup	
4.6 Test Conditions	
5 TEST ITEMS	
5.1 Emission Tests	23
5.2 Immunity Tests	27
ANNEX A TEST RESULTS	



A.1 Radiated Emission	
A.2 Conducted Emission	37
A.3 Harmonic Current Emissions	39
A.4 Voltage Fluctuations & Flicker	40
A.5 Electrostatic Discharge Immunity	
A.6 Radio Frequency Electromagnetic Field Immunity	41
A.7 Electrical Fast Transient/Burst Immunity	41
A.8 Surge Immunity	41
A.9 Immunity to Conducted Disturbances Induced by RF Fields	42
A.10 Power Frequency Magnetic Fields Immunity	42
A.11 Voltage Dips and Short Interruptions Immunity	42
ANNEX B TEST SETUP PHOTOS	43
B.1 Radiated Emission	43
B.2 Conducted Emission	44
B.3 Voltage Fluctuations and Flicker	45
B.4 Electrostatic Discharge Immunity	
B.5 Radiated, Radio Frequency Electromagnetic Field Immunity	
B.6 Electrical Fast Transient/Burst Immunity	47
B.7 Surge Immunity	49
B.8 Immunity to Conducted Disturbances Induced by RF Fields	50
B.9 Power Frequency Magnetic Fields Immunity	51
B.10 Voltage Dips and Short Interruptions Immunity	52
ANNEX C EUT EXTERNAL PHOTOS	53
ANNEX D EUT INTERNAL PHOTOS	55



1 GENERAL INFORMATION

1.1 Identification of the Testing Laboratory

Company Name	Shenzhen BALUN Technology Co., Ltd.		
Address 1	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road,		
Address	Nanshan District, Shenzhen, Guangdong Province, P. R. China		
Address 2	Room 104, 204, 205, Building 1, No. 6, Industrial South Road,		
Address 2	Songshan Lake District, Dongguan, Guangdong, China		
Phone Number	+86 755 6685 0100		

1.2 Identification of the Responsible Testing Location

Test Location	Shenzhen BALUN Technology Co., Ltd.				
Address 1	Block B, 1st FL, Baisha Science and Technology Park, Shahe Xi Road,				
Address	Nanshan District, Shenzhen, Guangdong Province, P. R. China				
Address 2	Room 104, 204, 205, Building 1, No. 6, Industrial South Road,				
Address Z	Songshan Lake District, Dongguan, Guangdong, China				
	The laboratory is a testing organization accredited by China National				
Accreditation Certificate	Accreditation Service for Conformity Assessment (CNAS) according to				
	ISO/IEC 17025. The accreditation certificate number is L6791.				
	All measurement facilities used to collect the measurement data are				
Description	located at Block B, 1st FL, Baisha Science and Technology Park,				
Description	Shahe Xi Road, Nanshan District, Shenzhen, Guangdong Province, P.				
	R. China				

1.3 Laboratory Condition

Ambient Temperature	20°C~25°C
Ambient Relative Humidity	45% - 55%
Ambient Pressure	100 kPa - 102 kPa

1.4Announce

- (1) The test report reference to the report template version v1.1.
- (2) The test report is invalid if not marked with the signatures of the persons responsible for preparing and approving the test report.
- (3) The test report is invalid if there is any evidence and/or falsification.
- (4) The results documented in this report apply only to the tested sample, under the conditions and modes of operation as described herein.
- (5) This document may not be altered or revised in any way unless done so by BALUN and all revisions are duly noted in the revisions section.
- (6) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.



2 PRODUCT INFORMATION

2.1 Applicant Information

Applicant	Shenzhen SOFAR SOLAR Co., Ltd.		
Address	401, Building 4, AnTongDa Industrial Park, District 68, XingDong		
Audress	Community, XinAn Street, BaoAn District, Shenzhen, China.		

2.2 Manufacturer Information

Manufacturer	Shenzhen SOFAR SOLAR Co., Ltd.		
Addroso	401, Building 4, AnTongDa Industrial Park, District 68, XingDong		
Address	Community, XinAn Street, BaoAn District, Shenzhen, China.		

2.3 Factory Information

Factory	Dongguan SOFAR SOLAR Co.,Ltd.			
Address	1F - 6F, Building E, No. 1 JinQi Road, Bihu Industrial Park, Wulian			
Audress	Village, Fenggang Town, Dongguan City.			

2.4 General Description for Equipment under Test (EUT)

EUT Name	Solar Gird-tied Inverter		
Mode Name Under Test	SOFAR 3300TL-G3		
Series Model Name	SOFAR 1100TL-G3, SOFAR 1600TL-G3, SOFAR 2200TL-G3, SOFAR		
	2700TL-G3, SOFAR 3000TL-G3, SOFAR 3300TL-G3		
Hardware Version	N/A		
Software Version	N/A		
Dimensions (Approx.)	N/A		
Weight (Approx.)	N/A		
	Model No.: SOFAR 1100TL-G3, SOFAR 1600TL-G3, SOFAR		
	2200TL-G3, SOFAR 2700TL-G3, SOFAR 3000TL-G3, SOFAR		
	3300TL-G3. The model SOFAR 1600TL-G3 and SOFAR3300TL-G3		
Remark	were tested and the worst data are recorded in this report, since the		
	electrical circuit design, layout, components used, internal wiring And		
	function were identical for the above models, please find more		
	specification from below table.		



Note: not application.

2.6 Technical Information

	AC Ports	From mains to AC power adapter.			
Interfaces	DC Ports	From power supply to EUT.			
present	Telecom	No Tologom Dorto			
on the	Port	No Telecom Ports.			
EUT	Signal	No Signal parts			
	Ports	No Signal ports.			
		The equipment is Solar Gird-tied Inverter, the above EUT information			
About the Product		was declared by manufacturer and for more detailed features			
		description, please refer to the manufacturer's specifications or user's			
		manual.			

<hr/>	00545	00515	00515	00515	00515	00515
Model	SOFAR	SOFAR	SOFAR	SOFAR	SOFAR	SOFAR
Item	1100TL-G3	1600TL-G3	2200TL-G3	2700TL-G3	3000TL-G3	3300TL-G3
Heat sink size	25	53*253.3*26.5m	ım	271*253.3*40mm		
Inverter inductance		0.99mH * 2pcs		0.676mH * 2 pcs		
Bus capacitance	470uF /500V* 2 pcs			470uF/550V * 3 pcs		
size	303X260.5X118				321X260.5X13 [,]	1.5
weight	5.5kg			6.3kg		
Operating voltage range	50-500V			50-550V		
Grid-connected starting voltage	70V			70V 70V		
Full load MPPT range	110-450V	150-450V	200-450V	250-500V	275-500V	300-500V
Max. Input power	1500W	2200W	3000W	3700W	4100W	4500W
Max. Output current	5.3A	7.7A	10.6A	13A	14.5A	16A
Max. Output power	1100VA	1600VA	2200VA	2700VA	3000VA	3300VA





Solar Grid-tied Inverter

Model No.	SOFAR 3300TL-G3
Max.DC Input Voltage	550V
Operating MPPT Voltage Rar	nge 50~550V
Max. Input Current	12A
Max. PV lsc	15A
Nominal Grid Voltage	L/N/PE,230Vac
Max. Output Current	16A
Nominal Grid Frequency	50/60Hz
Max. Output Power	3300VA
Power Factor	1(adjustable+/-0.8)
Ingress protection	IP65
Operating Temperature Rar	nge _30~+60℃
Тороlоду	Non-isolated
Protective Class	Class I
Manufacturer:Shenzhen SOF	ARSOLAR Co., Ltd.
Address: 401, Building 4, AnTo	
Industrial Park, District 68, Xin Community, XinAn Street, Bao	
District, Shenzhen, China	ATT.
VDE0126-1-1,VDE-AR-N4105, IEC61727, IEC62116, UTE C15-712-1,AS4777	2=3
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3 SUMMARY OF TEST RESULTS

3.1 Test Standards

The objective of the report is to perform testing according to following standards:

No.	Identity	Document Title
1	EN 61000-6-1: 2019	Electromagnetic compatibility (EMC) Part 6-1: Generic standards —Immunity for residential, commercial and light-industrial environments.
2	EN 61000-6-3: 2007/A1:2011/AC:2012	Electromagnetic compatibility (EMC) Part 6-3: Generic standards — Emission standard for residential, commercial and light-industrial environments.
3	IEC 61000-6-1:2016	Electromagnetic compatibility (EMC) - Part 6-1: Generic standards - Immunity standard for residential, commercial and light-industrial environments
4	IEC 61000-6-3:2006+ AMD1:2010	Electromagnetic compatibility (EMC) - Part 6-3: Generic standards - Emission standard for residential, commercial and light-industrial environments
5	EN 61000-3-2: 2014	Electromagnetic compatibility (EMC) Part 3-2: Limits - Limits for harmonic current emissions (equipment input current <= 16 A per phase).
6	EN 61000-3-3: 2013	Electromagnetic Compatibility (EMC)– Part 3-3: Limits – Limitation of voltage changes, voltage fluctuations and flicker in public low – voltage supply systems, for equipment with rated current ≤16 A per phase and not subject to conditional connection.
7	IEC 61000-3-2:2018	Electromagnetic compatibility (EMC) - Part 3-2: Limits - Limits for harmonic current emissions (equipment input current ≤16 A per phase)
8	IEC 61000-3-3:2013+ AMD1:2017	Electromagnetic compatibility (EMC) - Part 3-3: Limits - Limitation of voltage changes, voltage fluctuations and flicker in public low - voltage supply systems, for equipment with rated current ≤ 16 A per phase and not subject to conditional connection



No	Base Standard	Description		Test Verdict	Result	Remark
Emi	ssion					
1	EN 61000-6-3&	Radiated	Below 1 GHz	Pass	Annex A.1	
	IEC 61000-6-3	Emission	Above 1 GHz	N/A		Note 1
	EN 61000-6-3&	Conducted	AC Ports	Pass	-	
2	IEC 61000-6-3	Emission	DC Ports	N/A	Annex A.2	Note 2
			Telecom Ports	N/A		
3	EN 61000-3-2& IEC 61000-3-2	Harmonic Curren	t Emissions	Pass	Annex A.3	
4	EN 61000-3-3& IEC 61000-3-2	Voltage Fluctuati	ons & Flicker	Pass	Annex A.4	
Imm	nunity			·	·	
5	IEC 61000-4-2	Electrostatic Disc Immunity	charge	Pass	Annex A.5	
6	IEC 61000-4-3	Radiated RF Electric Field Immunity	ctromagnetic	Pass	Annex A.6	
		Electrical Fast	AC Ports	Pass	Annex A.7	
7	IEC 61000-4-4	Transient/Burst	DC Ports	Pass		
		Immunity	Signal Ports	N/A		
8			AC Ports	Pass	Annex A.8	
0	IEC 61000-4-5	Surge Immunity	DC Ports	Pass	Annex A.o	
		Immunity to	AC Ports	Pass		
		Conducted	DC Ports	Pass		
9	9 IEC 61000-4-6 Disturbances Induced by RF Fields		Signal Ports	N/A	Annex A.9	
10	IEC 61000-4-8	Power-frequency	magnetic field	Pass	Annex A.10	
11	IEC 61000-4-11	Voltage Dips and Short Interruptions Immunity	AC Port	Pass	Annex A.11	

Note 1: The highest internal frequency of the EUT is less than 108MHz, the measurement shall only be made up to 1GHz.

Note 2: There is no need for Conducted Emission DC Ports test to be performed on this product with the cable shorter than 30m.

Note 3: The difference between the EUT (test samples in this report) and testing sample of report No. BL-SZ1960495-402, which was issued by Shenzhen BALUN Technology Co., Ltd. on Aug. 23, 2019 is that change Applicant address, Manufacturer address and add factory information. EUT is the same. Except Radiated RF Electromagnetic Field Immunity supplemented the test of 1.4GHz ~ 6GHz, all test result please refer to report No. BL-SZ1960495-402, which was issued by Shenzhen BALUN Technology Co., Ltd. on Aug. 23, 2019.



The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.

Measurement	Value
Conducted emissions (9 kHz-30 MHz)	3.23 dB
Radiated emissions (30 MHz-1 GHz)	4.30 dB



4 GENERAL TEST CONFIGURATIONS

4.1 Test Environments

Environment Parameter		Selected Values During Tests						
	Temperature	Voltage	Relative Humidity	Ambient Pressure				
Normal Temperature, Normal Voltage (NTNV)	23°C~25°C	AC 230V/ 50 Hz DC 360V	50%-55%	100 to 102 kPa				

4.2 Test Equipment List

Radiated Emission Test For Frequency Below 1 GHz										
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use				
EMI Receiver	ROHDE&SCHWA RZ	ESRP	101036	2019.06.12	2020.06.11	X				
Test Antenna- Bi-Log	SCHWARZBECK	VULB 9163	9163-977	2019.07.21	2020.07.20	\boxtimes				
Test Antenna- Horn	SCHWARZBECK	BBHA 9120D	9120D-1600	2018.07.11	2020.07.10					
Anechoic Chamber	EMC Electronic Co., Ltd	20.10*11.60 *7.35m	N/A	2018.08.08	2020.08.07	\boxtimes				

Radiated Emission Test For Frequency Above 1 GHz										
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use				
EMI Receiver	KEYSIGHT	N9038A	MY53220118	2018.11.07	2019.11.06					
Test Antenna-	SCHWARZBECK	VULB 9163	9163-624	2019.07.21	2020.07.20					
Bi-Log		VOLD 9103		2019.07.21						
Test Antenna-	SCHWARZBECK	BBHA	9120D-1148	2018.07.11	2020.07.10					
Horn	SCHWARZDECK	9120D	91200-1140	2016.07.11	2020.07.10					
Anechoic	RAINFORD	9m*6m*6m	N/A	2019.02.20	2021.02.18					
Chamber	KAINFURD		IN/A	2019.02.20	2021.02.16					

Conducted disturbance Test										
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use				
EMI Receiver	ROHDE&SCHWA RZ	ESRP	101036	2019.06.12	2020.06.11	\boxtimes				
LISN	SCHWARZBECK	NSLK 8127	8127-687	2019.06.12	2020.06.11					
LISN	SCHWARZBECK	NNLK 8129	8129-462	2018.11.07	2019.11.06	\boxtimes				
AMN	SCHWARZBECK	NNBM8124	8124-509	2019.06.12	2020.06.11					
AMN	SCHWARZBECK	NNBM8124	8124-510	2019.06.12	2020.06.11					
ISN	TESEQ	ISN T800	34449	2017.12.05	2019.12.04					
Shielded Enclosure	RAINFORD	9m*6m*6m	N/A	2019.02.20	2021.02.18	\boxtimes				



Voltage Fluctuations & Flicker and Harmonic Current Emissions Test										
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use				
HARMONICS,FLI										
CKER&POWER	LAPLACE INSTRUMENTS	AC2000A	377954	2018.11.07	2019.11.06	\boxtimes				
ANALYSER	INSTRUMENTS									
AC TESTING	EVERFINE	DDC1020	Y120984CJ7	2010 11 07	2010 11 06	\boxtimes				
POWER SOURCE	EVERFINE	DPS1030	331115	2018.11.07	2019.11.06					

Electrostatic Discharge Immunity Test									
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use			
ESD Test System	SCHLODER	SESD 30000	206253	2019.06.20	2020.06.19	\boxtimes			

	Radiated RF Electromagnetic Field Immunity Test							
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use		
Anechoic Chamber	RAINFORD	9m*6m*6m	N/A	2019.02.20	2021.02.18	\boxtimes		
Signal Generator	ROHDE&SCHW ARZ	SMB100A	177746	2019.06.10	2020.06.09	\boxtimes		
Power Amplifier	OPHIR RF	5225F	1037	N/A	N/A	\boxtimes		
Power Amplifier	OPHIR RF	5273F	1016	N/A	N/A	\boxtimes		
Power Meter	Agilent	E4419B	GB40201833	2018.11.15	2019.11.14	\boxtimes		
Directional Coupler	Werlantone	C5982-10	109275	N/A	N/A	\boxtimes		
Directional Coupler	Werlantone	CHP-273E	S00801z-01	N/A	N/A	\boxtimes		
Feld Strength Meter	Narda	EP601	511WX51129	2019.06.18	2020.06.17	\boxtimes		
Test Antenna- Bi-Log	SCHWARZBECK	VULB 9163	9163-624	2019.07.21	2020.07.20	\boxtimes		
Test Antenna- Horn	SCHWARZBECK	BBHA 9120D	9120D-1148	2018.07.11	2020.07.10	\boxtimes		
Mouth Simulator	B&K	4227	2423931	2018.11.15	2019.11.14			
Sound Calibrator	B&K	4231	2430337	2018.11.15	2019.11.14			
Sound Level Meter	B&K	NL-20	00844023	2018.11.15	2019.11.14			
Ear Simulator	B&K	4185	2409449	2018.11.15	2019.11.14			
Ear Simulator	B&K	4195	2418189	2018.11.15	2019.11.14			
Audio analyzer	B&K	UPL 16	100129	2018.11.15	2019.11.14			

Electrical Fast Transient/Burst Immunity Test									
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use			
EFT Test System	HTEC	HEFT 51	1331011	2019.05.07	2020.05.06	\boxtimes			
EFT coupling network	HTEC	ECDN 51	150601	2019.05.07	2020.05.06	\boxtimes			
EFT clamp	TESEQ	CDN 3425	25164	2019.05.07	2020.05.06				



	Transients and Surges Test										
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use					
SURGE Generator (AC/DC Ports)	HTEC	HCWG 70	151601	2019.05.07	2020.05.06	\boxtimes					
SURGE coupling network (AC/DC Ports)	HTEC	SCDN303P7	151602	2019.05.07	2020.05.06	\boxtimes					
SURGE Generator (Telecom Ports)	HTEC	HCOMB 70	143806	2019.05.07	2020.05.06						
SURGE coupling network (Telecom Ports)	HTEC	TCOMB-4	143807	2019.05.07	2020.05.06						

Immunity to Conducted Disturbances Induced by RF Fields								
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use		
CONDUCTED								
DISTURBANCES	Schloder GmbH	CDG 6000	126B1286	2018.06.13	2019.06.12			
TEST SYSTEM								
CDN-M2+3	Schloder GmbH	CDN	A2210276	2018.06.13	2019.06.12			
CDIN-IMZ+3		M2+M3-16	AZ210270	2010.00.13	2019.00.12	\square		
CDN-M1	Schloder GmbH	CDN-M1	A2010063	2018.11.07	2019.11.06			
CDN-M4	Schloder GmbH	CDN-M4	A2610002	2018.11.07	2019.11.06			
CDN-M5	Schloder GmbH	CDN-M5	A2560005	2018.11.07	2019.11.06			
Injection Probe	FCC	F-120-8M	190119	2018.04.19	2019.04.18			

Voltage Dips and Short Interruptions Immunity Test							
Description	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Use	
Voltage Fault							
Simulating	HTEC	HPFS303P	152301	2019.05.07	2020.05.06	\boxtimes	
Generator							
Voltage Fault	HTEC	HV3P30	152302	2019.05.07	2020.05.06	\boxtimes	
Coupling Network	TIEC		152302	2019.05.07	2020.05.00		



4.3 Test Enclosure list

Description	Manufacturer	Model	Serial No.	Length	Description	Use
PC	Dell	015K3N	N/A	N/A	Special Handled	
Laptop	Apple	A1465	N/A	N/A	N/A	
Printer	HP	DESKJET 1000	N/A	N/A	N/A	
Keyboard	Logitech	Y-BP62a	N/A	N/A	N/A	
Mouse	Logitech	M100	N/A	N/A	N/A	
USB disk	Kingston	N/A	N/A	N/A	N/A	
TF Card	Kingston	N/A	N/A	N/A	N/A	
VGA Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
HDMI Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
DVI Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
Coaxial video cable	N/A	N/A	N/A	2.0 m	Shielded with core	
iPhone	Apple	A1586	N/A	N/A	N/A	
Phone	MI	M4	N/A	N/A	N/A	
Bluetooth Earphone	SAMSUNG	Gear Circle	N/A	N/A	N/A	
Wireless Communication s Test Set	R&S	CMW500	142028	N/A	Cal. Due 2019.06.14	
WIFI Router	TP-LINK	TL-WDR7500 N/A		N/A	N/A	
Earphone	N/A	OPPO	N/A	1.1 m	N/A	
Car Battery	Camel	55530	N/A	N/A	12 V/55 Ah	
Artificial load	N/A	N/A	N/A	N/A	2.5 Ω/100 W	
Artificial load	N/A	N/A	N/A	N/A	5 Ω/100 W	
Electronic Load	ITECH	IT8511	N/A	N/A	N/A	
USB Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
DC Power Supply	ITECH	IT6863A	60001401068 7210006	N/A	N/A	
LCD Monitor	SAMSUNG	UA32C4000P	N/A	N/A	N/A	
LCD Monitor	Dell	U241HB	N/A	N/A	N/A	
RJ45 Cable	N/A	N/A	N/A	1.5 m	Shielded with core	
Chorma 62150H-1000S	Chorma	N/A	6215EF01558	N/A	IN 380/400V3~5 0A17.2Kw OUT 1000V15A1 5kW	\boxtimes



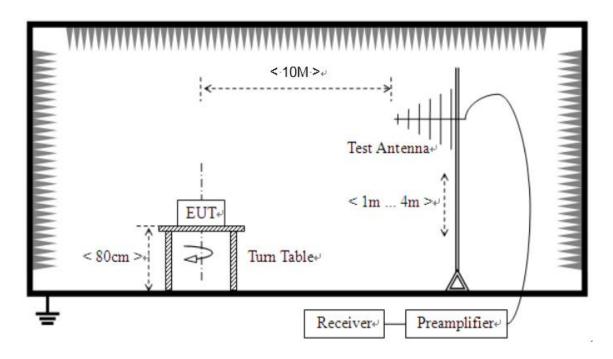
4.4 Test Configurations

Test Configurations (TC) No.	Description
TC01	The Full load Test mode
1001	EUT + Chorma 62150H-1000S
TC02	The Half load Test mode
1002	EUT + Chorma 62150H-1000S
TC03	The 10% load Test mode
1003	EUT + Chorma 62150H-1000S



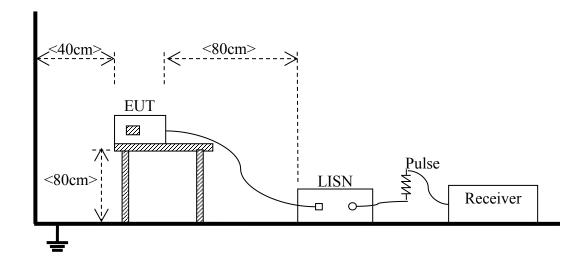
4.5 Description of Test Setup

Test Setup 1



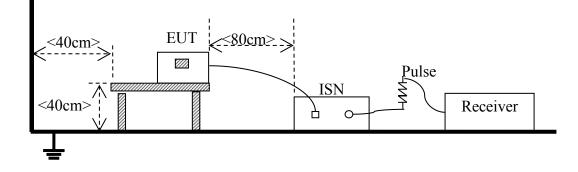
(For Radiated Emission Test (30 MHz-1 GHz))

Test Setup 2

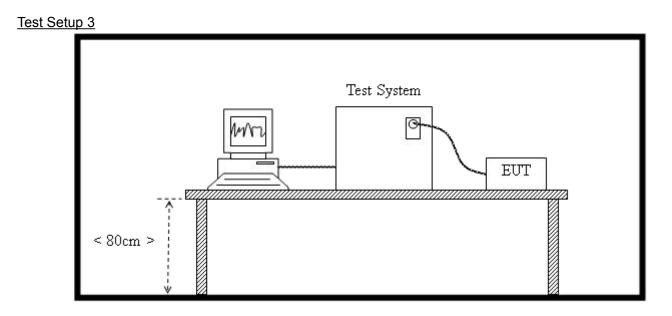


(For Conducted disturbance voltage at mains terminals Test)

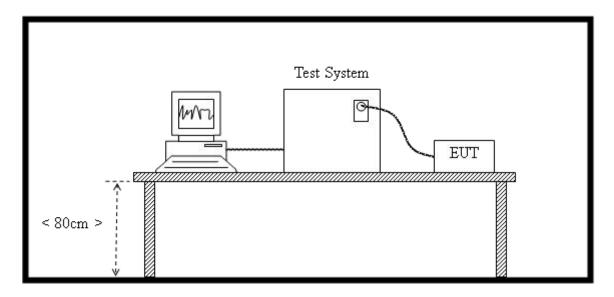


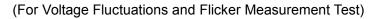


(For Conducted disturbance for asymmetric mode Test)

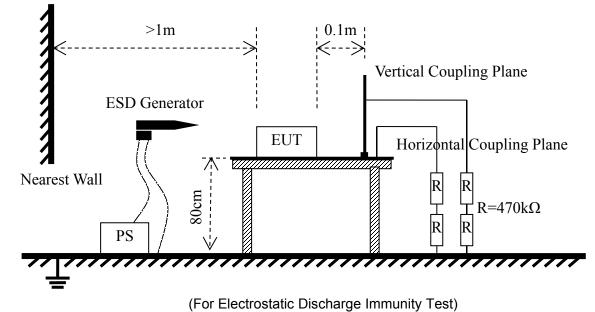


(For Harmonic Current Emissions Measurement Test)

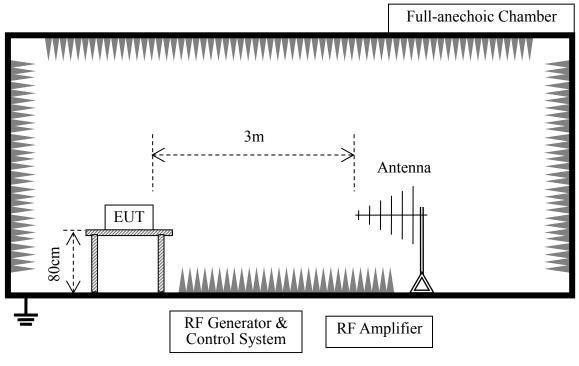


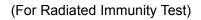




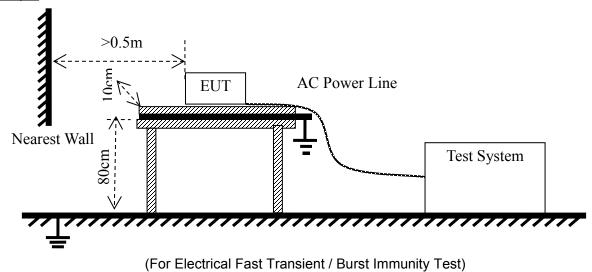


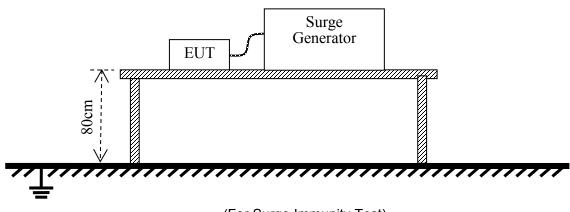






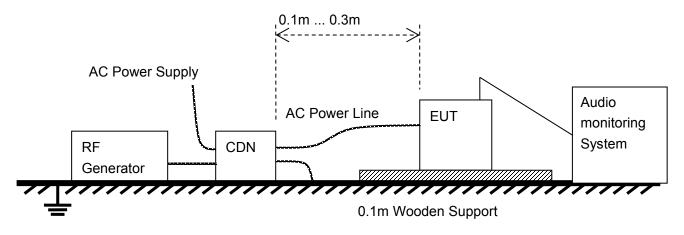




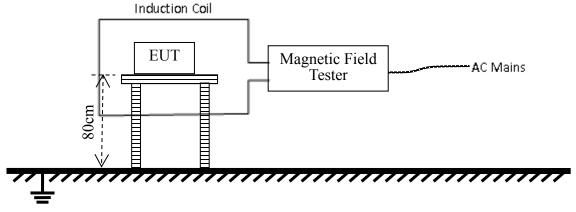


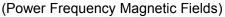




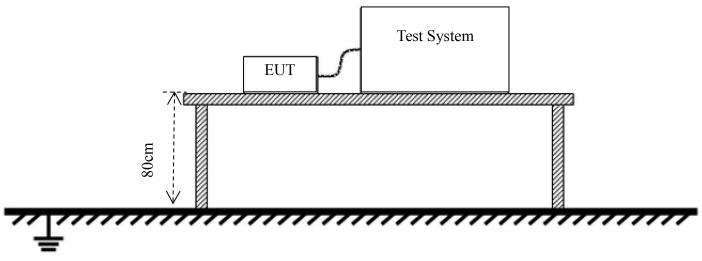


(For Immunity to Conducted Disturbances Induced By RF Fields Test)









(For Voltage Dips and Short Interruptions Immunity Test)



Test Case		Test Conditions
Dedicted Enviroism	Test Env.	NTNV
Radiated Emission, Below 1GHz	Test Setup	Test Setup 1
	Test Configuration	TC01-TC03 Note
Conducted Emission	Test Env.	NTNV
Conducted Emission,	Test Setup	Test Setup 2
AC Ports	Test Configuration	TC01-TC03 Note
	Test Env.	NTNV
Harmonic Current	Test Setup	Test Setup 4
Emissions	Test Configuration	TC01-TC03 Note
Valtere Eluctuations 0	Test Env.	NTNV
Voltage Fluctuations & Flicker	Test Setup	Test Setup 4
FIICKEI	Test Configuration	TC01-TC03 Note
Electrostatic Discharge	Test Env.	NTNV
	Test Setup	Test Setup 5
Immunity	Test Configuration	TC01-TC03 Note
Radiated RF	Test Env.	NTNV
Electromagnetic Field	Test Setup	Test Setup 6
Immunity	Test Configuration	TC01-TC03 Note
Electrical Fast	Test Env.	NTNV
Transient/Burst	Test Setup	Test Setup 7
Immunity, AC Port	Test Configuration	TC01-TC03 Note
Surge Immunity AC	Test Env.	NTNV
Surge Immunity, AC Ports	Test Setup	Test Setup 8
POILS	Test Configuration	TC01-TC03 Note
Immunity to Conducted	Test Env.	NTNV
Disturbances Induced	Test Setup	Test Setup 9
by RF Fields, AC Ports	Test Configuration	TC01-TC03 Note
Dower frequency	Test Env.	NTNV
Power-frequency	Test Setup	Test Setup 10
magnetic field	Test Configuration	TC01-TC03 Note
Voltage Ding and Object	Test Env.	NTNV
Voltage Dips and Short	Test Setup	Test Setup 11
Interruptions Immunity	Test Configuration	TC01-TC03 Note

Note: Based on client request, all normal using modes of the normal function were tested but only the worst test data of the worst mode is reported by this report. The Full load test mode is the worst test mode in this report.



5 TEST ITEMS

5.1 Emission Tests

5.1.1 Radiated Emission

5.1.1.1 Limit

Frequency range	Distance (at 3 m)	Distance (at 3 m) Distance (at 10 m)	
(MHz)	Quasi-Peak Limit (dBµV/m)	Quasi-Peak Limit (dBµV/m)	Quasi-Peak Limit (dBµV/m)
30 - 230	50	40	30
230 - 1000	57	47	37

NOTE:

- 1) The lower limit shall apply at the transition frequency.
- 2) Additional provisions may be required for cases where interference occurs.
- 3) Only apply to apparatus containing devices operating at frequencies more than 9 kHz.

5.1.1.2 Test Procedure

All Radiated Emission tests were performed in the azimuth plane. And test data and plots are recorded in this test report.

An initial pre-scan was performed in the chamber using the EMI Receiver in peak detection mode. Quasi-peak measurements were conducted based on the peak sweep graph. The EUT was measured by Bi-Log antenna with 2 orthogonal polarities.



5.1.2 Conducted Emission

5.1.2.1 Test Limit

AC Port

Frequency range	Class B		
(MHz)	Quasi-peak (dBuV)	Average (dBuV)	
0.15 - 0.50	66 to 56	56 to 46	
0.50 - 5	56	46	
5 - 30	60	50	

NOTE:

- 1) The lower limit shall apply at the band edges.
- 2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50 MHz.
- 3) It is tested under the low voltage which is for the distribution of AC electric power, the upper limit is generally accepted to be 1000 V.

DC Port

Frequency range	Class B		
(MHz)	Quasi-peak (dBuV)	Average (dBuV)	
0.15 - 0.50	79	66	
0.50 - 30	73	60	

NOTE:

- 1) The lower limit shall apply at the band edges.
- Applicable only to ports intended for connection to a local DC power network or a local battery by a connecting cable exceeding a length of 30 m.

Telecom Port

	Clas	s B
Frequency (MHz)	Quasi-peak (dBuV)	Average (dBuV)
0.15 - 0.50	84-74	74-64
0.50 - 30	74	64

NOTE:

- 1) The lower limit shall apply at the band edges.
- 2) The limit decreases linearly with the logarithm of the frequency in the range 0.15 0.50 MHz.
- 3) The current and voltage disturbance limits are derived for use with an impedance stabilization network (ISN) which presents a common mode (asymmetric mode) impedance of 150 Ω to telecommunication port under test.

5.1.2.2 Test Procedure

The EUT is connected to the power mains through a LISN which provides 50 Ω /50 μ H of coupling impedance for the measuring instrument. The test frequency range is from 150 kHz to 30 MHz. The maximum conducted interference is searched using Peak (PK), Quasi-peak (QP) and Average (AV) detectors; the emission levels that are more than the AV and QP limits, and that have narrow margins from the AV and QP limits will be re-measured with AV and QP detectors. Tests for both L phase and N phase lines of the power mains connected to the EUT are performed. Telecommunication port was checked to find out the maximum conducted emission



5.1.3 Harmonic Current Emissions

5.1.3.1 Limit

	Limits for Class	A equipmer	Limits f	or Class D eq	uipment	
odd ha	armonic	Even h	narmonics	Harmonic	Maximum	Maximum
Harmonic	Maximum	Harmonic	Maximum	order	permissibl	permissible
order	permissible	order	permissible	(n)	e harmonic	harmonic
(n)	harmonic	(n)	harmonic		current per	current A
	current A		current A		watt mA/W	
3	2.30	2	1.08	3	3.4	2.30
5	1.14	4	0.43	5	1.9	1.14
7	0.77	6	0.30	7	1.0	0.77
9	0.40	8≪n≪40	0.23X8/n	9	0.5	0.40
11	0.33			11	0.35	0.33
13	0.21			15≪n≪39	3.85/n	0.15X15/n
15≤n≤39	0.15X15/n					

Note: For Class B equipment, the harmonics of the input current shall not exceed the values given in Table "limits for Class A equipment" multiplied by a factor of 1,5.

For the purpose of harmonic current limitation, equipment is classified as follows:(Note :Class C equipment requirement not include in this standard.)

Class A:

- balanced three-phase equipment;
- household appliances, excluding equipment identified as class D;
- tools, excluding portable tools;
- dimmers for incandescent lamps;
- audio equipment.

Equipment not specified in one of the three other classes shall be considered as class A equipment. Class B:

- portable tools;
- arc welding equipment which is not professional equipment.

Class C:

- lighting equipment.

Class D:

Equipment having a specified power according to 6.2.2 less than or equal to 600 W, of the following types:

- personal computers and personal computer monitors;
- television receivers.

5.1.3.2 Test Procedure

The EUT is placed on the top of a wooden table 0.8m above the ground and operated to produce the maximum harmonic components under normal operating conditions for each successive harmonic component in turn.

The correspondent test program of test instrument to measure the current harmonics emanated from EUT is chosen. The measure time shall be not less than the necessary for the EUT to be exercised.



5.1.4 Voltage Fluctuations and Flicker Measurement

5.1.4.1 Limit

Test Item	Limit	Note			
Pst	1.0	Short-term flicker indicator			
Plt	0.65	Long-term flicker indicator			
Tdt	0.5	Maximum time that dt exceeds 3%			
dmax (%)	4%	Maximum relative voltage change			
dc (%)	3.3%	Relative steady-state voltage change			

5.1.4.2 Test Procedure

During the Flicker measurement, the measure time shall include that part of whole operation changes. The observation period for short-term flicker indicator is 10 minutes and the observation period for long-term flicker indicator is 2 hours. The test specifications refer the next table.

No.	Specification	Value
1	Test Frequency	50 Hz
2	Test Voltage	230 VAC
3	Waveform	Sine
4	Test Time	10 minutes for Pst; 2 hours for Plt



5.2 Immunity Tests

5.2.1 Test Performance Criteria for Immunity Test

5.2.1.1 General Performance Criteria

Туре	Description
	The apparatus shall continue to operate as intended during and after the test. No
Criterion A	degradation of performance or loss of function is allowed below a performance
	level specified by the manufacturer, when the apparatus is used as intended.
	The apparatus shall continue to operate as intended after the test. No degradation
Criterion B	of performance or loss of function is allowed below a performance level specified
	by the manufacturer, when the apparatus is used as intended.
Criterion C	Temporary loss of function is allowed, provided the function is self-recoverable or
	can be restored by the operation of the controls.



5.2.2 Electrostatic Discharge Immunity

5.2.2.1 Test Specification

Specification	Value				
Basic Standard	IEC 61000-4-2				
Discharge Impedance	330 Ohm / 150 pF				
Discharge Voltage	Air Discharge: 2 kV; 4 kV; 8 kV; Contact Discharge: 2 kV; 4 kV				
Polarity	Positive / Negative				
Number of Discharge	Minimum 20 times at each test point				
Discharge Mode	Single discharge				
Discharge Period	1 second minimum				

5.2.2.2 Test Procedure

1. Electrostatic discharges are applied only to those points and surfaces of the EUT that are accessible to users during normal operation.

2. The test is performed with at least ten single discharges on the pre-selected points in the most sensitive polarity.

3. The time interval between two successive single discharges is at least 1 second.

4. The ESD generator is held perpendicularly to the surface to which the discharge is applied and the return cable is at least 0.2 meters from the EUT.

5. Contact discharges are applied to the non-insulating coating, with the pointed tip of the generator penetrating the coating and contacting the conducting substrate.

6. Air discharges are applied with the round discharge tip of the discharge electrode approaching the EUT as fast as possible (without causing mechanical damage) to touch the EUT. After each discharge, the ESD generator is removed from the EUT and re-triggered for a new single discharge. The test is repeated until all discharges were completed.

7. At least ten single discharges (in the most sensitive polarity) are applied to the Horizontal Coupling Plane at points on each side of the EUT. The ESD generator is positioned vertically at a distance of 0.1 meters from the EUT with the discharge electrode touching the HCP.

8. At least ten single discharges (in the most sensitive polarity) are applied to the center of one vertical edge of the Vertical Coupling Plane in sufficiently different positions that the four faces of the EUT were completely illuminated. The VCP (dimensions 0.5 m*0.5 m) is placed vertically to and 0.1 meters from the EUT.



5.2.3 Radio Frequency Electromagnetic Field Immunity

5.2.3.1 Test Specification

Specification	Value				
Basic Standard	IEC 61000-4-3				
Frequency Range	80 MHz to 1000 MHz, 1400 MHz to 6000 MHz				
Field Strength	3 V/m or 1 V/m (unmodulated, r.m.s)				
Modulation	1 kHz sine wave, 80%, AM modulation				
Frequency Step	1% of fundamental				
Polarity of Antenna	Horizontal and Vertical				
Test Distance	3 m				
Antenna Height	1.5 m				
Dwell Time	3 seconds				

5.2.3.2 Test Procedure

1. The testing is performed in a fully anechoic chamber. The transmit antenna is located at a distance of 3 meters from the EUT.

2. The test signal is 80% amplitude modulated with a 1 kHz sine wave.

3. The frequency range is swept from 80 MHz to 1000 MHz and 1400 MHz to 6000 MHz with the exception of the exclusion band for transmitters, receivers and duplex transceivers. The rate of sweep does not exceed 1.5*10-3 decade/s. Where the frequency range is swept incrementally, the step size is 1% of fundamental.

4. The dwell time at each frequency shall be not less than the time necessary for the EUT to be able to respond.

5. The field strength level is 3 V/m for 80 MHz to 1000MHz, 1400 MHz to 6000 MHz.

6. The test is performed with the EUT exposed to both vertically and horizontally polarized fields on each of the four sides, but only the worst side data is reported in this report.



5.2.4 Electrical Fast Transient / Burst Immunity

5.2.4.1 Test Specification

Specification	Value				
Basic Standard	IEC 61000-4-4				
Teat Valtage	AC Power Port: 0.5 kV, 1 kV.				
Test Voltage	DC Power Ports, Telecom Ports: 0.25 kV, 0.5 kV.				
Polarity	Positive / Negative				
Impulse Frequency	5 kHz				
Impulse Wave Shape	5/50 ns				
Burst Duration	15 ms				
Burst Period	300 ms				
Test Duration	> 1 min				

NOTE:

- 1. The signal ports tests apply only to ports interfacing with cables whose total length according to the manufacturer's functional specification may exceed 3 m.
- 2. The DC ports test not applicable to input ports intended for connection to a battery or a rechargeable battery which must be removed or disconnected from the apparatus for recharging.
- 3. The EUT with a DC power input port intended for use with an AC-DC power adaptor shall be tested on the AC power input of the AC-DC power adaptor specified by the manufacturer or where none is so specified, using a typical AC-DC power adaptor.
- 4. The test applicable to DC power input ports and signal ports intended to be connected permanently to cables longer than 3 m.

5.2.4.2 Test Procedure

- 1. The EUT is tested with 1000 V discharges to the AC power input leads, 500 V for signal port and DC port.
- 2. Both positive and negative polarity discharges are applied.

3. The length of the "hot wire" from the coaxial output of the EFT generator to the terminals on the EUT should not exceed 1 m.

- 4. The duration time of each test sequential is 1min.
- 5. The transient / burst waveform is in accordance with IEC 61000-4-4, 5/50 ns.



5.2.5 Surge Immunity

5.2.5.1 Test Specification

Specification	Value				
Ports class	AC Power Port	DC Power Port			
Basic Standard	IEC 610	000-4-5			
Waveform	Voltage: 1.2/50 µs; Current:	Voltage: 1.2/50 µs; Current:			
waveloitti	8/20 μs	8/20 µs			
	line to ground 0.5 kV, 1 kV,				
Test Voltage	2 kV;	0.5k V			
	line to line 0.5 kV, 1 kV				
Polarity	Positive / Negative				
Phase Angle	0°, 90°, 180°, 270° N/A				
Repetition Rate	60 seconds				
Times	5 times per condition				

NOTE:

- 1. For ports where primary protection is intended, surges are applied at voltages up to 4 kV with the primary protectors fitted. Otherwise the 1 kV test level is applied without primary protection in place.
- 2. The DC ports test not applicable to input ports intended for connection to a battery or a rechargeable battery which must be removed or disconnected from the apparatus for recharging.
- 3. The EUT with a DC power input port intended for use with an AC-DC power adaptor shall be tested on the AC power input of the AC-DC power adaptor specified by the manufacturer or where none is so specified, using a typical AC-DC power adaptor.
- 4. DC ports which are not intended to be connected to a DC distribution network are treated as signal ports.

5.2.5.2 Test Procedure

The EUT and the auxiliary equipment are placed on a table of 0.8 m heights above a metal ground reference plane. The size of ground plane is greater than 1 m*1 m and project beyond the EUT by at least 0.1 m on all sides. The ground plane is connected to the protective earth. The length of power cord between the coupling device and the EUT is less than 2 meters (provided by the manufacturer).

The EUT is connected to the power mains through a coupling device that directly couples the surge interference signal. The surge noise is applied synchronized to the voltage phase at the zero crossing and the peak value of the AC voltage wave (positive and negative).

The surges are applied line to line and line(s) to earth. When testing line to earth the test voltage is applied successively between each of the lines and earth. Set up to the test level specified increased the test voltage. All lower levels including the selected test level are tested. The polarity of each surge level included positive and negative test pulses.



5.2.6 Immunity to Conducted Disturbances Induced by RF Fields

5.2.6.1 Test Specification

Specification	Value			
Basic Standard	IEC 61000-4-6			
Frequency Range	0.15 MHz – 80 MHz			
Field Strength	3 Vrms (unmodulated, r.m.s)			
Modulation	1 kHz sine wave, 80% AM			
Frequency Step	1% of fundamental			
Coupled Cable	AC Power Line; DC Power Line; Telecom Line			
Coupling Device	CDN-M2+3			

Note:

- 1) The DC port and signal port only apply to ports interfacing with cables whose total length according to the manufacturers functional specification may exceed 3 m.
- 2) The AC port only apply to input ports.
- 3) The test level can also be defined as the equivalent current into a 150 Ω load at signal ports.

5.2.6.2 Test Procedure

The EUT shall be tested within its intended operating and climatic conditions.

The test shall be performed with the test generator connected to each of the coupling and decoupling devices in turn, while the other non-excited RF input ports of the coupling devices are terminated by a 150 Ohm load resistor.

The test signal is 80% amplitude modulated with a 1 kHz sine wave.

The frequency range is swept from 150 kHz to 80 MHz, using the signal level established during the setting process and with a disturbance signal of 80% amplitude. The sweep rate shall not exceed 1.5*10-3 decades/s. The step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value where the frequency is swept incrementally.

The dwell time at each frequency shall not be less than the time necessary for the EUT to be exercised, and able to respond. Sensitive frequencies such as clock frequencies and harmonics or frequencies of dominant interest, shall be analyzed separately.

Attempts should be made to fully exercise the EUT during test, and to fully interrogate all exercise modes selected for susceptibility.



5.2.7 Power Frequency Magnetic Fields Immunity

5.2.7.1 Test Specification

Specification	Value
Basic Standard	IEC 61000-4-8
Field Frequency	50/60 Hz
Test Level	3 A/m
Polarity	Horizontal and Vertical
Test Duration	5 min

NOTE:

- 1. The test shall be carried out at the frequencies appropriate to the power supply frequency. Equipment intended for use in areas supplied only at one of these frequencies need only be tested at that frequency.
- 2. Applicable only to apparatus containing devices susceptible to magnetic fields.

5.2.7.2 Test Procedure

The EUT shall be subjected to the test magnetic field by using the induction coil of standard dimensions (1 m*1 m) and shown in Section 15.1. The induction coil shall then be rotated by 90°in order to expose the EUT to the test field with different orientations.



5.2.8 Voltage Dips and Short Interruptions Immunity

5.2.8.1 Test Specification

AC Ports

Specification	Value				
Basic Standard	IEC 61000-4-11				
Frequency	50/60Hz				
Voltage Dips	100% reduction: 10 ms;100% reduction: 20 ms;				
	30% reduction: 500/600 ms				
Voltage Interruptions	100% reduction: 5000/6000 ms				
Voltage Phase Angle	0°				

NOTE: Applicable only to AC input ports.

5.2.8.2 Test Procedure

The power cord is used as supplied by the manufacturer. The EUT was connected to the line output of the Voltage Dips and Interruption Generator.

The EUT is tested for a) 100% voltage dip of supplied voltage with duration of 10 ms; b) 100% voltage dip of supplied voltage with duration of 20 ms; c) 30% voltage dip of supplied voltage and duration 500 or 600 ms. Both of the dip tests are carried out for a sequence of three voltage dips with intervals of 10 seconds.

100% voltage interruption of supplied voltage with duration of 5000 or 6000 ms is followed, which is a sequence of three voltage interruptions with intervals of 10 seconds.

Voltage reductions occur at 0 degrees crossover point of the voltage waveform. The performance of the EUT is checked after the voltage dip or interruption.



ANNEX A TEST RESULTS

A.1 Radiated Emission

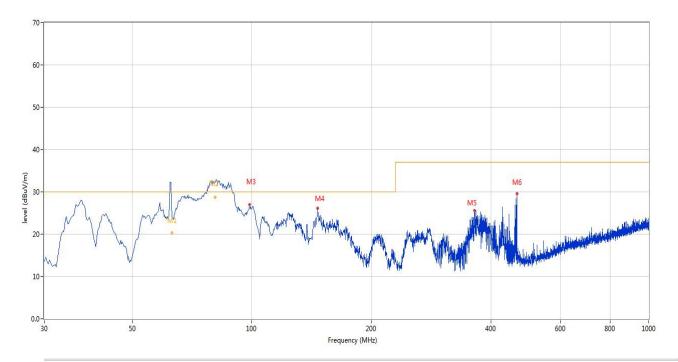
Note 1: The symbol of "--" in the table which means not application.

Note 2: Measurements shall be made with a quasi-peak measuring receiver in the frequency range 30 MHz to 1000 MHz. To reduce the testing time, a peak measuring receiver may be used instead of a quasi-peak measuring receiver. In case of dispute, measurement with a quasi-peak measuring receiver will take precedence.

Test Data and Plots

The Full load test mode

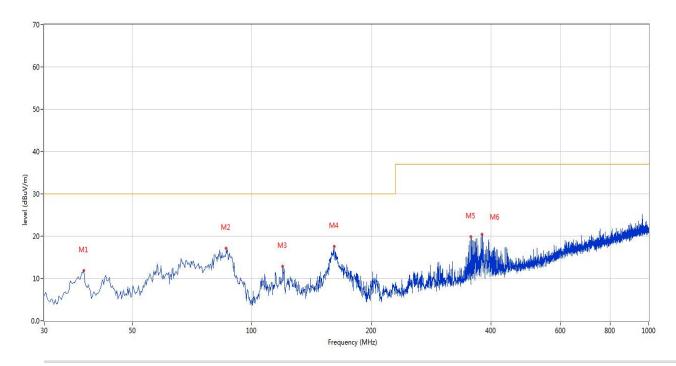
A.1.1 Test Antenna Vertical, 30 MHz – 1 GHz



No.	Frequency	Results	Factor (dB)	Limit	Over Limit	Detector	Table	Height	ANT	Verdict
	(MHz)	(dBuV/m)		(dBuV/m)	(dB)		(0)	(cm)		
1	62.921	23.37	-28.36	30.0	-6.63	Peak	70.00	352	Vertical	N/A
1*	62.921	20.31	-28.36	30.0	-9.69	QP	70.00	352	Vertical	Pass
2	80.682	31.48	-31.23	30.0	1.48	Peak	138.00	243	Vertical	N/A
2*	80.682	28.72	-31.23	30.0	-1.28	QP	138.00	243	Vertical	Pass
3	98.853	27.00	-30.29	30.0	-3.00	Peak	283.00	100	Vertical	Pass
4	146.371	26.17	-25.95	30.0	-3.83	Peak	132.00	100	Vertical	Pass
5	364.324	25.58	-24.05	37.0	-11.42	Peak	310.00	100	Vertical	Pass
6	465.906	29.52	-21.27	37.0	-7.48	Peak	35.00	100	Vertical	Pass



A.1.2 Test Antenna Horizontal, 30 MHz – 1 GHz



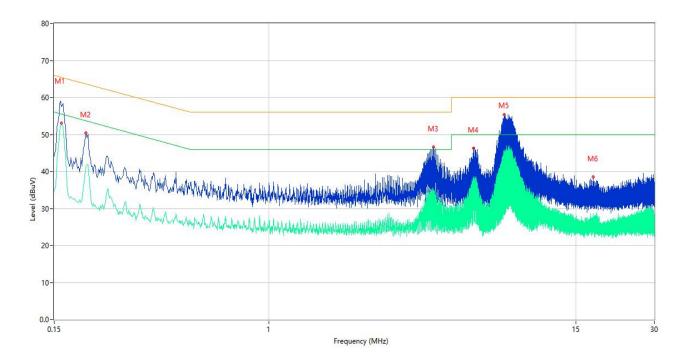
No.	Frequency	Results	Factor (dB)	Limit	Over Limit	Detector	Table	Height	ANT	Verdict
	(MHz)	(dBuV/m)		(dBuV/m)	(dB)		(0)	(cm)		
1	37.758	11.88	-27.03	30.0	-18.12	Peak	273.00	100	Horizontal	Pass
2	86.246	17.14	-31.10	30.0	-12.86	Peak	70.00	100	Horizontal	Pass
3	119.703	12.79	-28.08	30.0	-17.21	Peak	141.00	100	Horizontal	Pass
4	161.160	17.54	-25.87	30.0	-12.46	Peak	114.00	100	Horizontal	Pass
5	356.808	19.91	-24.24	37.0	-17.09	Peak	282.00	100	Horizontal	Pass
6	380.567	20.47	-23.50	37.0	-16.53	Peak	70.00	100	Horizontal	Pass



The Full load test mode

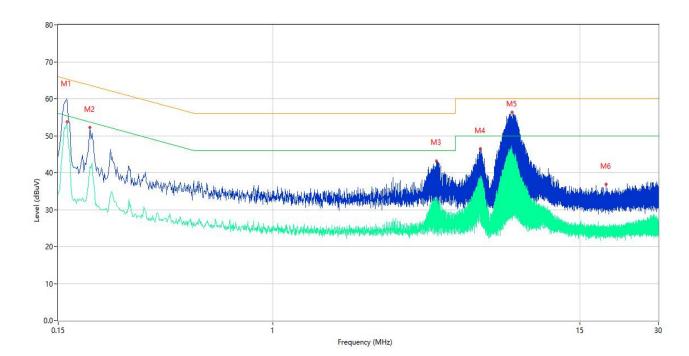
The worst test mode: The Working test mode

A.2.1 L Phase



No.	Frequency	Results	Factor (dB)	Limit (dBuV)	Over Limit	Detector	Line	Verdict
	(MHz)	(dBuV)			(dB)			
1	0.150	58.20	10.41	65.50	-7.30	Peak	L	Pass
1**	0.150	53.12	10.41	55.50	-2.38	AV	L	Pass
2	0.198	50.41	10.38	63.69	-13.28	Peak	L	Pass
2**	0.198	41.55	10.38	53.69	-12.14	AV	L	Pass
3	4.280	46.60	10.30	56.00	-9.40	Peak	L	Pass
3**	4.280	34.39	10.30	46.00	-11.61	AV	L	Pass
4	6.080	46.26	10.32	60.00	-13.74	Peak	L	Pass
4**	6.080	38.54	10.32	50.00	-11.46	AV	L	Pass
5	7.960	55.30	10.35	60.00	-4.70	Peak	L	Pass
5**	7.960	45.37	10.35	50.00	-4.63	AV	L	Pass
6	17.520	38.53	10.47	60.00	-21.47	Peak	L	Pass
6**	17.520	25.24	10.47	50.00	-24.76	AV	L	Pass





No.	Frequency	Results	Factor (dB)	Limit (dBuV)	Over Limit	Detector	Line	Verdict
	(MHz)	(dBuV)			(dB)			
1	0.162	60.21	10.40	65.36	-5.15	Peak	N	Pass
1**	0.162	53.43	10.40	55.36	-1.93	AV	N	Pass
2	0.198	52.22	10.38	63.69	-11.47	Peak	N	Pass
2**	0.198	41.60	10.38	53.69	-12.09	AV	N	Pass
3	4.238	43.21	10.31	56.00	-12.79	Peak	N	Pass
3**	4.238	32.11	10.31	46.00	-13.89	AV	N	Pass
4	6.242	46.38	10.33	60.00	-13.62	Peak	N	Pass
4**	6.242	39.25	10.33	50.00	-10.75	AV	N	Pass
5	8.240	56.36	10.35	60.00	-3.64	Peak	N	Pass
5**	8.240	45.09	10.35	50.00	-4.91	AV	N	Pass
6	18.892	36.85	10.52	60.00	-23.15	Peak	N	Pass
6**	18.892	24.98	10.52	50.00	-25.02	AV	N	Pass



A.3 Harmonic Current Emissions

E. U. T. Rated Power(W):	3300	Active Power(W):	3280	
Observation Period(s):	150	The Rate Of Total	0.35	
	150	Harmonic Distortion:	0.55	
Voltage(V):	240	System Power Supply:	Normal	
Frequency(Hz):	50.01	E. U. T.Category:	A	
Power Factor:	0.82	E. U. T.Results:	Pass	

Harmonic Number	Average (filtered) (mA)	Limit Current (mA)	% of Limit	max. Value (Filtered) (mA)	Limit Current (mA)	% of Limit	Assess ment
2	166	1080	15.4	173	1080	16.0	Pass
3	290	2300	12.6	296	2300	12.9	Pass
4	35	430	8.1	42	430	9.8	Pass
5	197	1140	17.3	203	1140	17.8	Pass
6	89	300	29.7	93	300	31.0	Pass
7	184	770	23.9	196	770	25.5	Pass
8	5	230	2.2	6	230	2.6	Pass
9	152	400	38.0	163	400	40.8	Pass
10	65	184	35.3	82	184	44.6	Pass
11	81	330	24.5	96	330	29.1	Pass
12	56	153.3	36.5	88	153.3	57.4	Pass
13	69	210	32.9	72	210	34.3	Pass
14	7	131.4	5.3	9	131.4	6.8	Pass
15	55	150	36.7	62	150	41.3	Pass
16	41	115	35.7	63	115	54.8	Pass
17	67	132.3	50.6	102	132.3	77.1	Pass
18	36	102.2	35.2	55	102.2	53.8	Pass
19	22	118.4	18.6	25	118.4	21.1	Pass
20	16	92	17.4	45	92	48.9	Pass
21	21	107.1	19.6	26	107.1	24.3	Pass
22	38	83.6	45.5	65	83.6	77.8	Pass
23	40	97.8	40.9	76	97.8	77.7	Pass
24	32	76.7	41.7	35	76.7	45.6	Pass
25	36	90	40.0	67	90	74.4	Pass
26	26	70.8	36.7	46	70.8	65.0	Pass
27	16	83.3	19.2	18	83.3	21.6	Pass
28	22	65.7	33.5	35	65.7	53.3	Pass
29	39	77.6	50.3	52	77.6	67.0	Pass
30	28	61.3	45.7	35	61.3	57.1	Pass
31	26	72.6	35.8	56	72.6	77.1	Pass



32	18	57.5	31.3	37	57.5	64.3	Pass
33	42	68.2	61.6	46	68.2	67.4	Pass
34	33	54.1	61.0	36	54.1	66.5	Pass
35	51	64.3	79.3	57	64.3	88.6	Pass
36	22	51.1	43.1	36	51.1	70.5	Pass
37	39	60.8	64.1	42	60.8	69.1	Pass
38	15	48.4	31.0	18	48.4	37.2	Pass
39	22	57.7	38.1	49	57.7	84.9	Pass
40	18	46	39.1	23	46	50.0	Pass

A.4 Voltage Fluctuations & Flicker

Test Parameter	Limit	Measurement Value	Verdict
Pst	1.0	0.1539	Pass
Plt	0.65	0.56	Pass
Tdt	0.5	0.00	Pass
dmax (%)	4%	0.311%	Pass
dc (%)	3.3%	0.371%	Pass

A.5 Electrostatic Discharge Immunity

Test Points	Discharge Level (kV)	Discharge Mode	Number of Discharge	Verdict
HCP	±2, ±4	Contact	20	Pass
VCP	±2, ±4	Contact	20	Pass
Faceplate	±2, ±4	Contact	240	Pass
Screw (four)	±2, ±4	Contact	80	Pass
Кеу	±2, ±4, ±8	Air	20	Pass
Screen	±2, ±4, ±8	Air	20	Pass
Shell	±2, ±4	Contact	240	Pass
Crack	±2, ±4, ±8	Air	40	Pass

Note: Performance of the all modes comply with the performance criteria in Criterion B.



A.6 Radio Frequency Electromagnetic Field Immunity

Antenna Polarity	Frequency (MHz)	Side	Field Strength (V/m)	Verdict
		Front	3	Pass
	80 1000	Back	3	Pass
	80 – 1000	Left	3	Pass
Vertical		Right	3	Pass
Vertical		Front	3	Pass
	1400 – 6000	Back	3	Pass
		Left	3	Pass
		Right	3	Pass
		Front	3	Pass
	80 1000	Back	3	Pass
	80 – 1000	Left	3	Pass
Llorizontol		Right	3	Pass
Horizontal		Front	3	Pass
	1400 – 6000	Back	3	Pass
	1400 - 8000	Left	3	Pass
		Right	3	Pass

Note: Performance of the all modes comply with the performance criteria in Criterion A.

A.7 Electrical Fast Transient/Burst Immunity

Test Data (AC Power Port)

Test Point	Polarity	Test Level (kV)	Verdict
AC Port	+ / -	0.5, 1	Pass

Test Data (DC Power Port)

Test Point	Polarity	Test Level (kV)	Verdict
DC Port	+ / -	0.5	Pass

Note: Performance of the all modes comply with the performance criteria in Criterion B.

A.8 Surge Immunity

Test Data (AC Power Port)

Coupling Line	Polarity	Voltage (kV)	Verdict
L-N	+ / -	0.5, 1	Pass
L-PE	+ / -	0.5, 1, 2	Pass
N-PE	+ / -	0.5, 1, 2	Pass

Test Data (DC Power Port)

Coupling Line	Polarity	Voltage (kV)	Verdict
DC Port	+ / -	0.5	Pass

Note: Performance of the all modes comply with the performance criteria in Criterion B.



A.9 Immunity to Conducted Disturbances Induced by RF Fields

Test Data (AC Power Port)

Test Point	Frequency (MHz)	Field Strength (V/m)	Verdict
AC Port	0.15 - 80	3	Pass

Test Data (DC Power Port)

Test Point	Frequency (MHz)	Field Strength (V/m)	Verdict
DC Port	0.15 - 80	3	Pass

Note: Performance of the all modes comply with the performance criteria in Criterion A.

A.10 Power Frequency Magnetic Fields Immunity

Test Point	Test Level (A/m)	Verdict
X	30	Pass
Y	30	Pass
Z	30	Pass

Note: Performance of the all modes comply with the performance criteria in Criterion A.

A.11 Voltage Dips and Short Interruptions Immunity

Test Mode	Voltage Reduction	Duration (ms)	Times	Interval (sec)	Verdict
	100%	10	3	10	Pass
Voltage Dips	100%	20	3	10	Pass
	30%	500	3	10	Pass
Voltage Interruptions	100%	5000	3	10	Pass

Note: Voltage Dips 100% Voltage Reduction performance of the all modes comply with the performance criteria in Criterion B. Voltage Dips 30% Voltage Reduction and Voltage Interruptions performance of the all modes comply with the performance criteria in Criterion C.



ANNEX B TEST SETUP PHOTOS

B.1 Radiated Emission

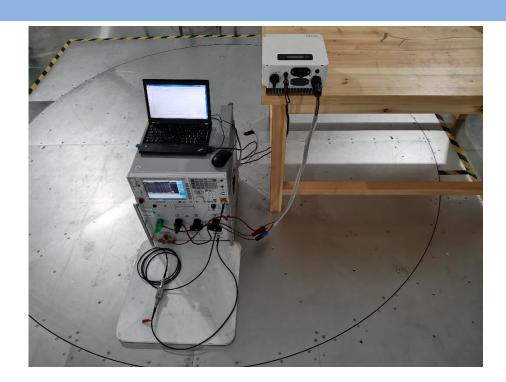
Below 1 GHz







B.2 Conducted Emission



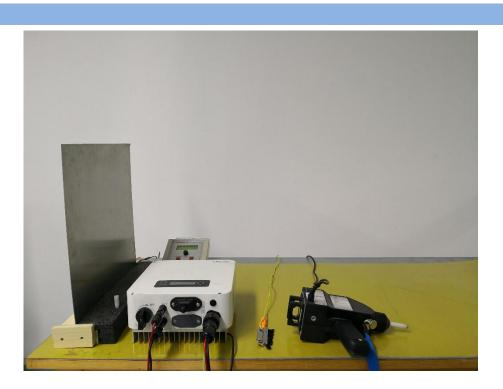


B.3 Voltage Fluctuations and Flicker





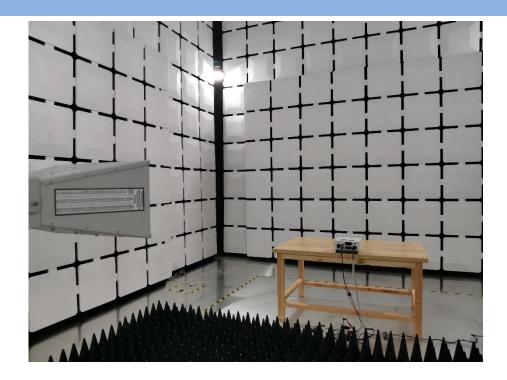
B.4 Electrostatic Discharge Immunity



B.5 Radiated, Radio Frequency Electromagnetic Field Immunity

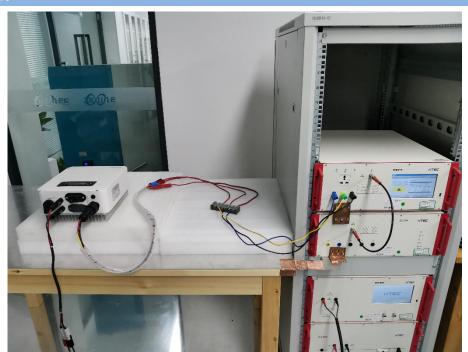






B.6 Electrical Fast Transient/Burst Immunity

AC Port





DC Port



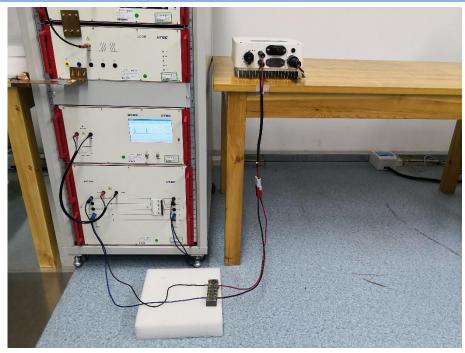




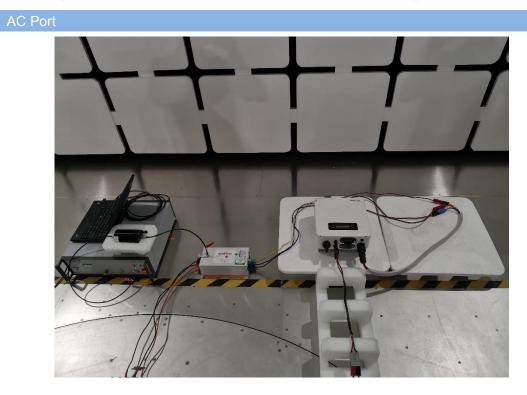




DC Port



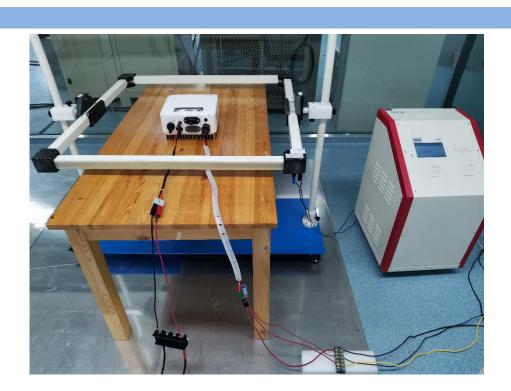
B.8 Immunity to Conducted Disturbances Induced by RF Fields







B.9 Power Frequency Magnetic Fields Immunity





B.10 Voltage Dips and Short Interruptions Immunity

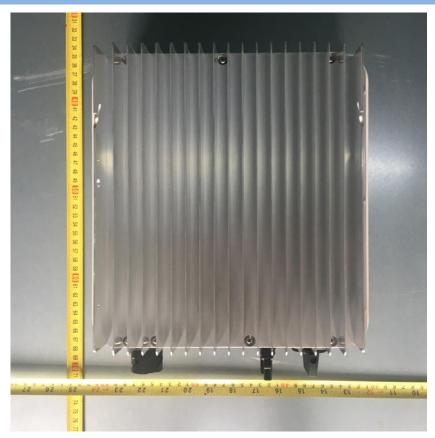




ANNEX C EUT EXTERNAL PHOTOS



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REAR VIEW OF EUT
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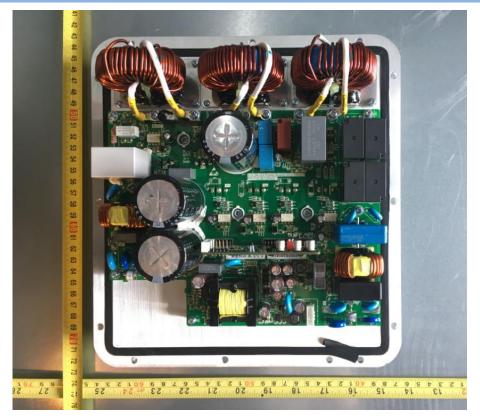
CLOSE UP





ANNEX D EUT INTERNAL PHOTOS

EUT UNCOVER VIEW

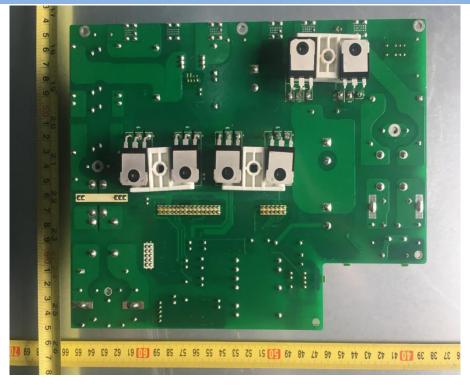


MAIN BOARD TOP VIEW

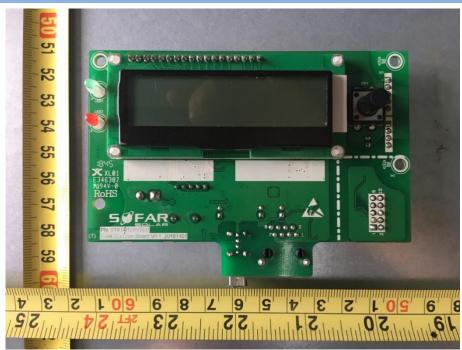




MAIN BOARD REAR VIEW

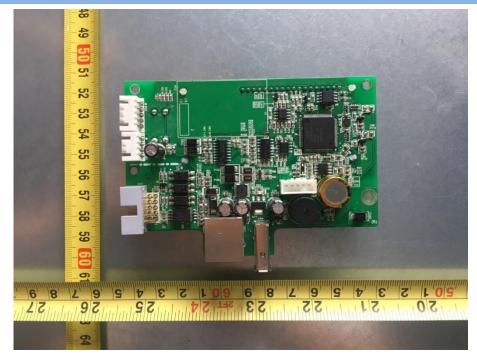


MAIN BOARD TOP VIEW

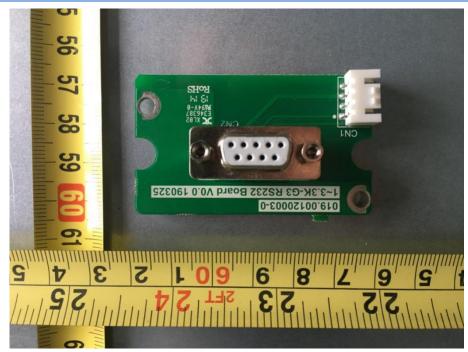




MAIN BOARD REAR VIEW

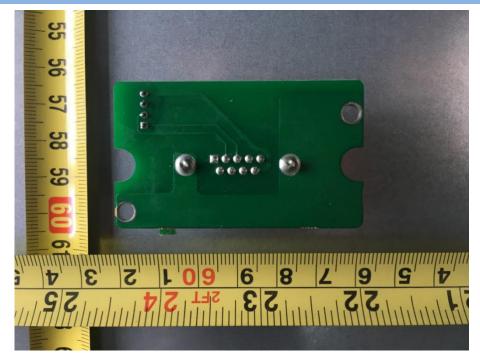


MAIN BOARD TOP VIEW





MAIN BOARD REAR VIEW



--END OF REPORT--